TLV5614 2.7-V TO 5.5-V 12-BIT 3-µS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

SLAS188B - SEPTEMBER 1998 - REVISED APRIL 2003

- Four 12-Bit D/A Converters
- Programmable Settling Time of Either 3 μs or 9 μs Typ
- TMS320, (Q)SPI[™], and Microwire[™] Compatible Serial Interface
- Internal Power-On Reset
- Low Power Consumption: 8 mW, Slow Mode – 5-V Supply 3.6 mW, Slow Mode – 3-V Supply
- Reference Input Buffer
- Voltage Output Range . . . 2× the Reference Input Voltage
- Monotonic Over Temperature

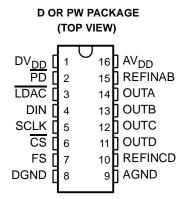
description

The TLV5614 is a quadruple 12-bit voltage output digital-to-analog converter (DAC) with a flexible 4-wire serial interface. The 4-wire serial interface allows glueless interface to TMS320, SPI, QSPI, and Microwire serial ports. The TLV5614 is programmed with a 16-bit serial word comprised of a DAC address, individual DAC control bits, and a 12-bit DAC value. The device has provision for two supplies: one digital supply for the serial interface (via pins DV_{DD} and DGND), and one for

- Dual 2.7-V to 5.5-V Supply (Separate Digital and Analog Supplies)
- Hardware Power Down (10 nA)
- Software Power Down (10 nA)
- Simultaneous Update

applications

- Battery Powered Test Instruments
- Digital Offset and Gain Adjustment
- Industrial Process Controls
- Machine and Motion Control Devices
- Communications
- Arbitrary Waveform Generation



the DACs, reference buffers, and output buffers (via pins AV_{DD} and AGND). Each supply is independent of the other, and can be any value between 2.7 V and 5.5 V. The dual supplies allow a typical application where the DAC is controlled via a microprocessor operating on a 3 V supply (also used on pins DV_{DD} and DGND), with the DACs operating on a 5 V supply. Of course, the digital and analog supplies can be tied together.

The resistor string output voltage is buffered by a x2 gain rail-to-rail output buffer. The buffer features a Class AB output stage to improve stability and reduce settling time. A rail-to-rail output stage and a power-down mode makes it ideal for single voltage, battery based applications. The settling time of the DAC is programmable to allow the designer to optimize speed versus power dissipation. The settling time is chosen by the control bits within the 16-bit serial input string. A high-impedance buffer is integrated on the REFINAB and REFINCD terminals to reduce the need for a low source impedance drive to the terminal. REFINAB and REFINCD allow DACs A and B to have a different reference voltage then DACs C and D.

The TLV5614 is implemented with a CMOS process and is available in a 16-terminal SOIC package. The TLV5614C is characterized for operation from 0°C to 70°C. The TLV5614I is characterized for operation from -40° C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

SPI and QSPI are trademarks of Motorola, Inc. Microwire is a trademark of National Semiconductor Corporation.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



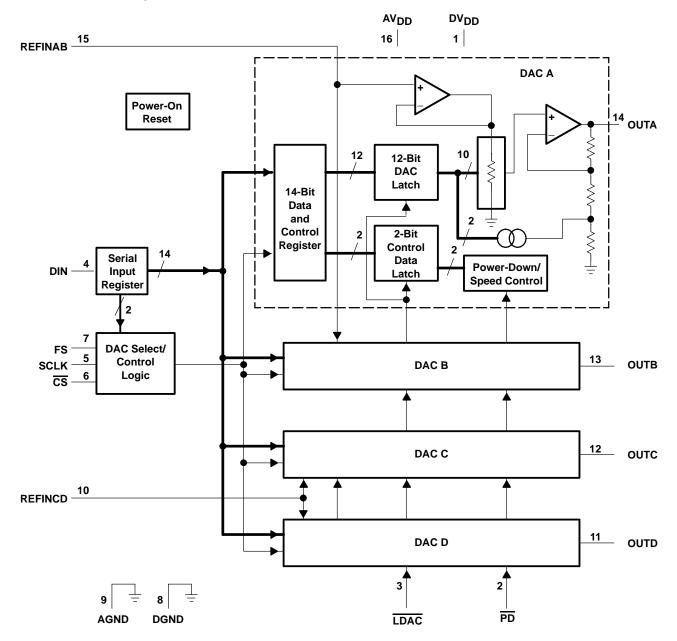
TLV5614 2.7-V TO 5.5-V 12-BIT 3- μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

SLAS188B – SEPTEMBER 1998 – REVISED APRIL 2003

AVAILABLE OPTIONS										
		PACKAGE								
TA	SOIC (D)	TSSOP (PW)	WSP [†] (YE)							
0°C to 70°C	TLV5614CD	TLV5614CPW								
-40°C to 85°C	TLV5614ID	TLV5614IPW	TLV5614IYE							

[†] Wafer Scale Packaging, also called Bumped Dice. See Figure 17.

functional block diagram





TLV5614 2.7-V TO 5.5-V 12-BIT 3-µS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

SLAS188B - SEPTEMBER 1998 - REVISED APRIL 2003

Terminal Functions

TERMIN	AL		
NAME	NO.	1/0	DESCRIPTION
AGND	9		Analog ground
AVDD	16		Analog supply
CS	6	-	Chip select. This terminal is active low.
DGND	8		Digital ground
DIN	4	Ι	Serial data input
DVDD	1		Digital supply
FS	7	I	Frame sync input. The falling edge of the frame sync pulse indicates the start of a serial data frame shifted out to the TLV5614.
PD	2	I	Power down pin. Powers down all DACs (overriding their individual power down settings), and all output stages. This terminal is active low.
LDAC	3	I	Load DAC. When the LDAC signal is high, no DAC output updates occur when the input digital data is read into the serial interface. The DAC outputs are only updated when LDAC is low.
REFINAB	15	Ι	Voltage reference input for DACs A and B.
REFINCD	10	Ι	Voltage reference input for DACs C and D.
SCLK	5	Ι	Serial clock input
OUTA	14	0	DACA output
OUTB	13	0	DACB output
OUTC	12	0	DACC output
OUTD	11	0	DACD output

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, (DV _{DD} , AV _{DD} to GND)	
Supply voltage difference, (AV _{DD} to DV _{DD})	
Digital input voltage range	
Reference input voltage range	–0.3 V to AV _{DD} + 0.3 V
Operating free-air temperature range, T _A : TLV5614C	0°C to 70°C
TLV5614I	–40°C to 85°C
Storage temperature range, T _{stg}	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



TLV5614 2.7-V TO 5.5-V 12-BIT 3-μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

SLAS188B - SEPTEMBER 1998 - REVISED APRIL 2003

recommended operating conditions

		MIN	NOM	MAX	UNIT
	5-V supply	4.5	5	5.5	
Supply voltage, AV _{DD} , DV _{DD}	3-V supply	2.7	3	3.3	V
1 Park Jacob Partial Second and the new Yo	DV _{DD} = 2.7 V	2			
High-level digital input voltage, VIH	DV _{DD} = 5.5 V	2.4			V
Level and d'alter for of only and the second	DV _{DD} = 2.7 V			0.6	
Low-level digital input voltage, VIL	DV _{DD} = 5.5 V			1	V
	5-V supply, See Note 1	0	2.048	V _{DD} -1.5	
Reference voltage, V _{ref} to REFINAB, REFINCD terminal	3-V supply, See Note 1	0	1.024	V _{DD} -1.5	V
Load resistance, RL		2	10		kΩ
Load capacitance, CL				100	pF
Serial clock rate, SCLK				20	MHz
	TLV5614C	0		70	
Operating free-air temperature	TLV5614I	-40		85	°C

NOTE 1: Voltages greater than AV_{DD}/2 cause output saturation for large DAC codes.

electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted)

static DAC specifications

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Resolution			12			bits
	Integral nonlinearity (INL), end p	oint adjusted	See Note 2		±1.5	±4	LSB
	Differential nonlinearity (DNL)		See Note 3		±0.5	±1	LSB
E _{ZS}	Zero scale error (offset error at zero scale)		See Note 4			±12	mV
	Zero scale error temperature co	efficient	See Note 5		10		ppm/°C
EG	Gain error		See Note 6			±0.6	% of FS voltage
	Gain error temperature coefficie	nt	See Note 7		10		ppm/°C
DODD	Dawen averally rejection ratio	Zero scale	Coo Natao 8 and 8		-80		dB
PSRR	Power supply rejection ratio	Full scale	See Notes 8 and 9		-80		dB

NOTES: 2. The relative accuracy or integral nonlinearity (INL) sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale excluding the effects of zero code and full-scale errors.

3. The differential nonlinearity (DNL) sometimes referred to as differential error, is the difference between the measured and ideal 1 LSB amplitude change of any two adjacent codes. Monotonic means the output voltage changes in the same direction (or remains constant) as a change in the digital input code.

4. Zero-scale error is the deviation from zero voltage output when the digital input code is zero.

5. Zero-scale-error temperature coefficient is given by: $E_{ZS} TC = [E_{ZS} (T_{max}) - E_{ZS} (T_{min})]/V_{ref} \times 10^6/(T_{max} - T_{min})$. 6. Gain error is the deviation from the ideal output (2 V_{ref} - 1 LSB) with an output load of 10 kΩ excluding the effects of the zero-error.

7. Gain temperature coefficient is given by: $E_G TC = [E_G(T_{max}) - E_G(T_{min})]/V_{ref} \times 10^6/(T_{max} - T_{min})$.

8. Zero-scale-error rejection ratio (EZS-RR) is measured by varying the AV_D from 5 ± 0.5 V and 3 ± 0.3 V dc, and measuring the proportion of this signal imposed on the zero-code output voltage.

Full-scale rejection ratio (EG-RR) is measured by varying the AV_{DD} from 5 ± 0.5 V and 3 ± 0.3 V dc and measuring the proportion 9. of this signal imposed on the full-scale output voltage after subtracting the zero scale change.



electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted) (continued)

individual DAC output specifications

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V	O Voltage output range	RL = 10 kΩ	0		AV _{DD} -0.4	V
	Output load regulation accuracy	R _L = 2 kΩ vs 10 kΩ		0.1	0.25	% of FS voltage

reference inputs (REFINAB, REFINCD)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
VI	Input voltage range	See Note 10		0		AV _{DD} -1.5	V
RI	Input resistance				10		MΩ
CI	Input capacitance			5		pF	
	Reference feed through	REFIN = 1 V _{pp} at 1 kHz + 1.024 V dc (see Note 11)	024 V dc		-75		dB
	Defense en land han duidth		Slow		0.5		N 41 1-
	Reference input bandwidth	REFIN = 0.2 V _{pp} + 1.024 V dc large signal			1		MHz

NOTES: 10. Reference input voltages greater than $V_{DD}/2$ cause output saturation for large DAC codes.

11. Reference feedthrough is measured at the DAC output with an input code = 000 hex and a V_{ref} (REFINAB or REFINCD) input = $1.024 \text{ Vdc} + 1 \text{ V}_{pp}$ at 1 kHz.

digital inputs (DIN, CS, LDAC, PD)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Ι _Η	High-level digital input current	$V_{I} = V_{DD}$			±1	μΑ
١ _{IL}	Low-level digital input current	$V_{I} = 0 V$			±1	μA
Cl	Input capacitance			3		pF

power supply

	PARAMETER	TEST CONDITION	TEST CONDITIONS				UNIT
IDD		5-V supply,	Slow		1.6	2.4	
	Deven even have a second	No load, Clock running, All inputs 0 V or V _{DD}	Fast		3.8	5.6	mA
	Power supply current	3-V supply,	Slow		1.2	1.8	
		No load, Clock running, All inputs 0 V or DV _{DD}	Fast		3.2	4.8	mA
	Power down supply current (see Figure 12)		-		10		nA



TLV5614 2.7-V TO 5.5-V 12-BIT 3-μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN SLAS188B – SEPTEMBER 1998 – REVISED APRIL 2003

electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted) (continued)

analog output dynamic performance

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT	
05	O data dalam anda	$C_{L} = 100 \text{ pF}, R_{L} = 10 \text{ k}\Omega,$	Fast		5		V/µs	
SR	Output slew rate	V _O = 10% to 90%, V _{ref} = 2.048 V, 1024 V	Slow		1		V/µs	
		To ± 0.5 LSB, C _L = 100 pF,	Fast		3	5.5		
t _S	Output settling time	$R_L = 10 \text{ k}\Omega$, See Notes 12 and 14	Slow		9	20	μs	
		To ± 0.5 LSB, C _L = 100 pF,	Fast		1		_	
t _{s(c)}	Output settling time, code to code	$R_L = 10 \text{ k}\Omega$, See Note 13	Slow		2		μs	
	Glitch energy	Code transition from 7FF to 800	Code transition from 7FF to 800				nV-sec	
SNR	Signal-to-noise ratio	Sinewave generated by DAC,	040 4514		74			
S/(N+D)	Signal to noise + distortion	Reference voltage = 1.024 at 3 V and 2. f _s = 400 KSPS,	.048 at 5 V,		66			
THD	Total harmonic distortion	$f_{OUT} = 1.1 \text{ kHz}$ sinewave,	-68		dB			
SFDR	Spurious free dynamic range	$C_L = 100 \text{ pF},$ $R_L = 10 \text{ k}\Omega,$ BW = 20 kHz			70			

NOTES: 12. Settling time is the time for the output signal to remain within ±0.5 LSB of the final measured value for a digital input code change of FFF hex to 080 hex for 080 hex to FFF hex.

13. Settling time is the time for the output signal to remain within ±0.5 LSB of the final measured value for a digital input code change of one count.

14. Limits are ensured by design and characterization, but are not production tested.

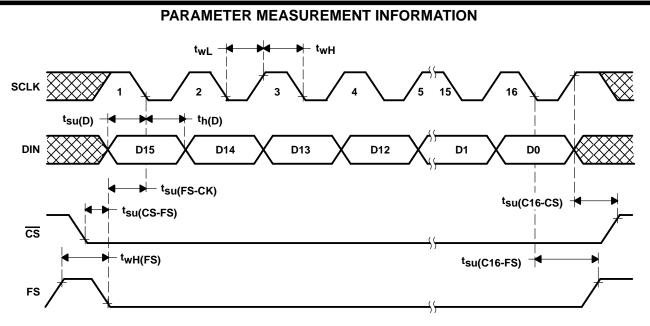


TLV5614 2.7-V TO 5.5-V 12-BIT 3-μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN SLAS188B – SEPTEMBER 1998 – REVISED APRIL 2003

electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted) (continued)

digital input timing requirements

		MIN	NOM	MAX	UNIT
t _{su} (CS–FS)	Setup time, CS low before FS↓	10			ns
tsu(FS–CK)	Setup time, FS low before first negative SCLK edge	8			ns
^t su(C16–FS)	Setup time, sixteenth negative SCLK edge after FS low on which bit D0 is sampled before rising edge of FS	10			ns
^t su(C16–CS)	Setup time. The first positive SCLK edge after D0 is sampled before \overline{CS} rising edge. If FS is used instead of the SCLK positive edge to update the DAC, then the setup time is between the FS rising edge and \overline{CS} rising edge.	10			ns
^t wH	Pulse duration, SCLK high	25			ns
t _{wL}	Pulse duration, SCLK low	25			ns
t _{su(D)}	Setup time, data ready before SCLK falling edge	8			ns
^t h(D)	Hold time, data held valid after SCLK falling edge	5			ns
^t wH(FS)	Pulse duration, FS high	20			ns

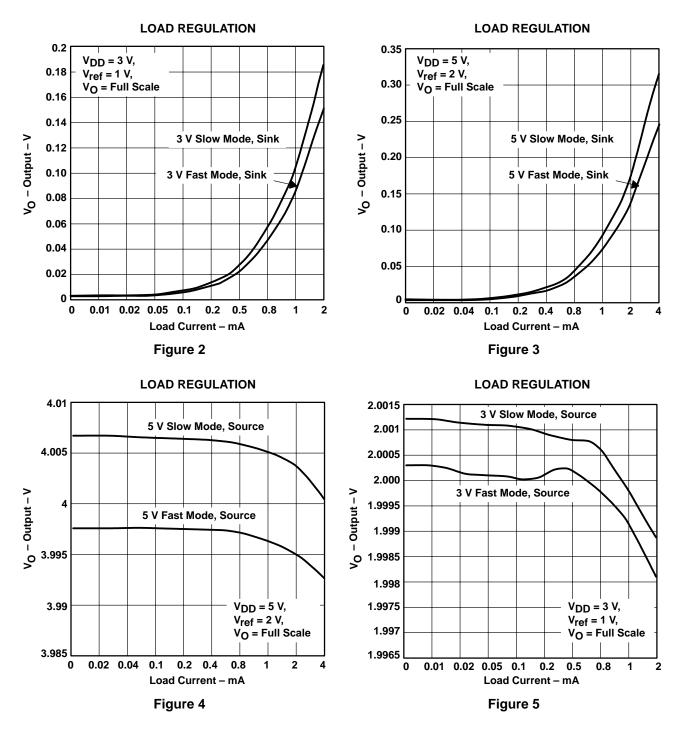






TLV5614 2.7-V TO 5.5-V 12-BIT 3- μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

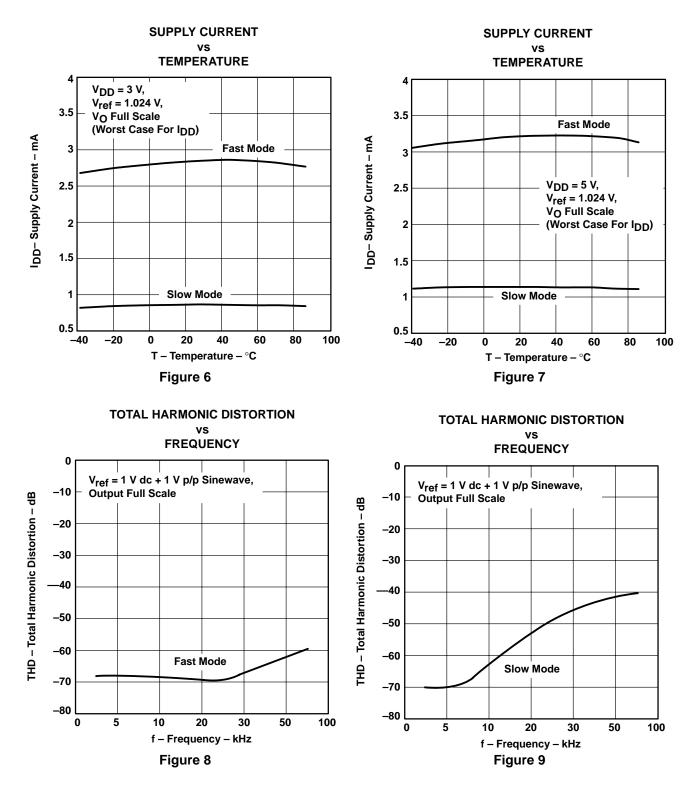
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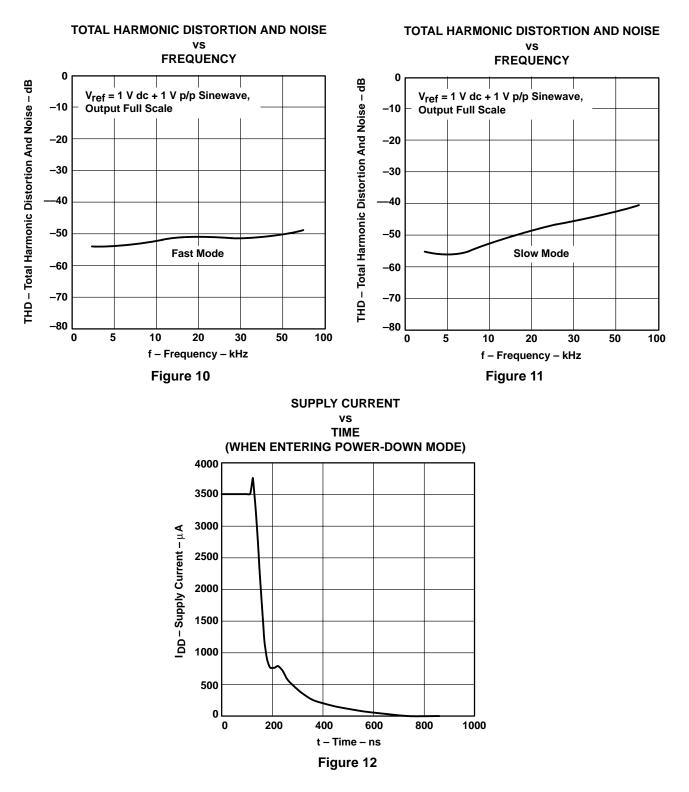


TLV5614 2.7-V TO 5.5-V 12-BIT 3-µS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

SLAS188B - SEPTEMBER 1998 - REVISED APRIL 2003

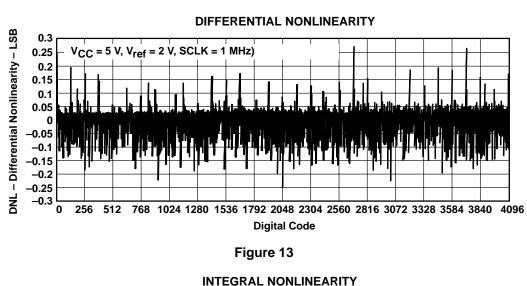








SLAS188B - SEPTEMBER 1998 - REVISED APRIL 2003



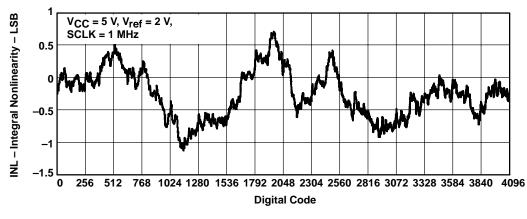


Figure 14



general function

The TLV5614 is a 12-bit single supply DAC based on a resistor string architecture. The device consists of a serial interface, speed and power down control logic, a reference input buffer, a resistor string, and a rail-to-rail output buffer.

The output voltage (full scale determined by external reference) is given by:

$$2 \text{ REF } \frac{\text{CODE}}{2^n} [V]$$

where REF is the reference voltage and CODE is the digital input value within the range of 0_{10} to $2^{n}-1$, where n=12 (bits). The 16-bit data word, consisting of control bits and the new DAC value, is illustrated in the *data format* section. A power-on reset initially resets the internal latches to a defined state (all bits zero).

serial interface

Explanation of data transfer: First, the device has to be enabled with \overline{CS} set to low. Then, a falling edge of FS starts shifting the data bit-per-bit (starting with the MSB) to the internal register on the falling edges of SCLK. After 16 bits have been transferred or FS rises, the content of the shift register is moved to the DAC latch which updates the voltage output to the new level.

The serial interface of the TLV5614 can be used in two basic modes:

- Four wire (with chip select)
- Three wire (without chip select)

Using chip select (four wire mode), it is possible to have more than one device connected to the serial port of the data source (DSP or microcontroller). The interface is compatible with the TMS320[™] DSP family. Figure 15 shows an example with two TLV5614s connected directly to a TMS320 DSP.

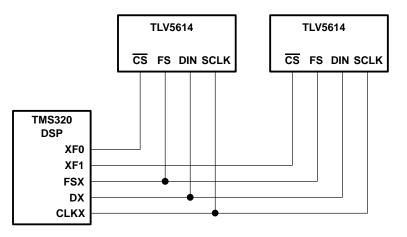


Figure 15. TMS320 Interface

TMS320 is a trademark of Texas Instruments.



serial interface (continued)

If there is no need to have more than one device on the serial bus, then \overline{CS} can be tied low. Figure 16 shows an example of how to connect the TLV5614 to a TMS320, SPI, or Microwire port using only three pins.

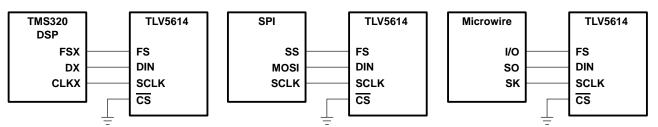


Figure 16. Three-Wire Interface

Notes on SPI and Microwire: Before the controller starts the data transfer, the software has to generate a falling edge on the I/O pin connected to FS. If the word width is 8 bits (SPI and Microwire), two write operations must be performed to program the TLV5614. After the write operation(s), the DAC output is updated automatically on the next positive clock edge following the sixteenth falling clock edge.

serial clock frequency and update rate

The maximum serial clock frequency is given by:

$$f_{SCLKmax} = \frac{1}{t_{wH(min)} + t_{wL(min)}} = 20 \text{ MHz}$$

The maximum update rate is:

$$f_{UPDATEmax} = \frac{1}{16 \left(t_{wH(min)} + t_{wL(min)} \right)} = 1.25 \text{ MHz}$$

Note that the maximum update rate is a theoretical value for the serial interface since the settling time of the TLV5614 has to be considered also.

data format

The 16-bit data word for the TLV5614 consists of two parts:

Control bits (D15...D12)

(D11...D0) New DAC value

D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
A1	A0	PWR	SPD		New DAC value (12 bits)										

X: don't care	
---------------	--

SPD: Speed control bit.	$1 \rightarrow fast mode$
PWR: Power control bit.	$1 \rightarrow power down$

```
0 \rightarrow \text{slow mode}
0 \rightarrow normal operation
```



In power-down mode, all amplifiers within the TLV5614 are disabled. A particular DAC (A, B, C, D) of the TLV5614 is selected by A1 and A0 within the input word.

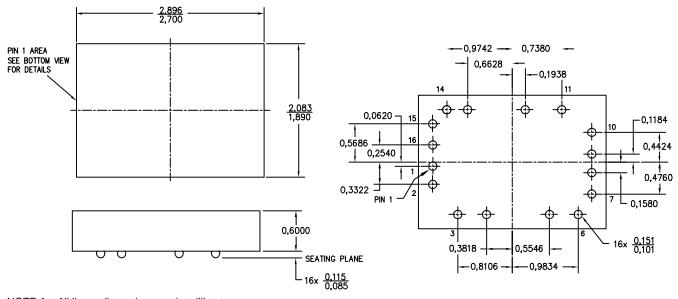
A0	DAC
0	А
1	В
0	C C
1	0
	A0 0 1 0

Using TLV5614IYE, Bumped Dice

- Melting point of eutectic solder is 183°C.
- Recommended peak reflow temperatures are in the 220°C to 230°C range.
- The use of underfill is required. The use of underfill greatly reduces the risk of thermal mismatch fails.

Underfill is an epoxy/adhesive that may be added during the board assembly process to improve board level/system level reliability. The process is to dispense the epoxy under the dice after die attach reflow. The epoxy adheres to the body of the device and to the printed-circuit board. It reduces stress placed upon the solder joints due to the thermal coefficient of expansion (TCE) mismatch between the board and the component. Underfill material is highly filled with silica or other fillers to increase an epoxy's modulus, reduce creep sensitivity, and decrease the material's TCE.

The recommendation for peak flow temperatures of 220°C to 230°C is based on general empirical results that indicate that this temperature range is needed to facilitate good wetting of the solder bump to the substrate or circuit board pad. Lower peak temperatures may cause nonwets (cold solder joints).



NOTE A: All linear dimensions are in millimeters.

NOTE B: This drawing is subject to change without notice.

NOTE C: Scale = 18x





TLV5614 interfaced to TMS320C203 DSP

hardware interfacing

Figure 17 shows an example of how to connect the TLV5614 to a TMS320C203 DSP. The serial port is configured in burst mode, with FSX generated by the TMS320C203 to provide the frame sync (FS) input to the TLV5614. Data is transmitted on the DX line, with the serial clock input on the CLKX line. The general-purpose input/output port bits IO0 and IO1 are used to generate the chip select (CS) and DAC latch update (LDAC) inputs to the TLV5614. The active low power down (PD) is pulled high all the time to ensure the DACs are enabled.

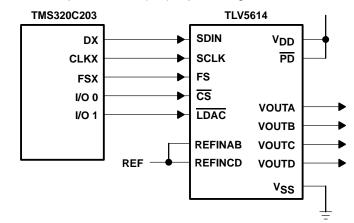


Figure 18. TLV5614 Interfaced With TMS320C203

software

The application example outputs a differential in-phase (sine) signal between the VOUTA and VOUTB pins, and its quadrature (cosine) signal as the differential signal between VOUTC and VOUTD.

The on-chip timer is used to generate interrupts at a fixed frequency. The related interrupt service routine pulses $\overline{\text{LDAC}}$ low to update all 4 DACs simultaneously, then fetches and writes the next sample to all 4 DACs. The samples are stored in a look-up table, which describes two full periods of a sine wave.

The synchronous serial port of the DSP is used in burst mode. In this mode, the processor generates an FS pulse preceding the MSB of every data word. If multiple, contiguous words are transmitted, a violation of the tsu(C16–FS) timing requirement occurs. To avoid this, the program waits until the transmission of the previous word has been completed.



TLV5614 2.7-V TO 5.5-V 12-BIT 3- μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

SLAS188B - SEPTEMBER 1998 - REVISED APRIL 2003

APPLICATION INFORMATION

;_____ _____ ; Processor: TMS320C203 runnning at 40 MHz ; Description: ; This program generates a differential in-phase (sine) on (OUTA-OUTB) and it's ; quadrature (cosine) as a differential signal on (OUTC-OUTD). ; The DAC codes for the signal samples are stored as a table of 64 12-bit values, ; describing 2 periods of a sine function. A rolling pointer is used to address the ; table location in the first period of this waveform, from which the DAC A samples ; are read. The samples for the other 3 DACs are read at an offset to this rolling ; pointer: Offset from rolling pointer DAC Function 0 А sine ; inverse sine 16 ; B С cosine 8 ; inverse cosine24 D : ; The on-chip timer is used to generate interrupts at a fixed rate. The interrupt ; service routine first pulses LDAC low to update all DACs simultaneously ; with the values which were written to them in the previous interrupt. Then all ; 4 DAC values are fetched and written out through the synchronous serial interface ; Finally, the rolling pointer is incremented to address the next sample, ready for ; the next interrupt. ; © 1998, Texas Instruments Inc. ; _ _ -_____ ;-----I/O and memory mapped regs -----.include "regs.asm" ;-----jump vectors -----.ps Oh b start b int1 int23 timer_isr; b b ------ variables -----temp .equ 0060h r_ptr .equ 0061h equ 0061h iosr_stat .equ 0062h DACa_ptr .equ 0063h DACb_ptr .equ 0064h .equ 0065h .equ 0066h DACc_ptr DACd_ptr ;-----constants------; DAC control bits to be OR'ed onto data ; all fast mode DACa_control .equ 01000h DACb_control .equ 05000h DACc_control .equ 09000h DACd_control .equ 0d000h ;----- tables ------02000h .ds sinevals .word 00800h .word 0097Ch .word 00AE9h .word 00C3Ah .word 00D61h .word 00E53h .word 00F07h .word 00F76h .word 00F9Ch .word 00F76h .word 00F07h .word 00E53h



.word	00D61h 00C3Ah
.word .word	00C3AN 00AE9h
.word	0097Ch
.word	00800h
.word	00684h
.word .word	00517h 003C6h
.word	00329Fh
.word	001ADh
.word	000F9h
.word	0008Ah
.word .word	00064h 0008Ah
.word	00005AN 000F9h
.word	001ADh
.word	0029Fh
.word	003C6h
.word .word	00517h 00684h
.word	0088411 00800h
.word	0097Ch
.word	00AE9h
.word	00C3Ah
.word	00D61h
.word .word	00E53h 00F07h
.word	00F76h
.word	00F9Ch
.word	00F76h
.word	00F07h
.word .word	00E53h 00D61h
.word	00D0111 00C3Ah
.word	00AE9h
.word	0097Ch
.word	00800h
.word	00684h 00517h
.word .word	0031711 003C6h
.word	0029Fh
.word	001ADh
.word	000F9h
.word	0008Ah
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.word	00517h
.word	00684h



TLV5614 2.7-V TO 5.5-V 12-BIT 3- μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

SLAS188B - SEPTEMBER 1998 - REVISED APRIL 2003

APPLICATION INFORMATION

;_____ ; Main Program ;-----.ps 1000h .entry start ;-; disable interrupts ; -; disable maskable interrupts INTM setc splk #0ffffh, IFR; clear all interrupts splk #0004h, IMR; timer interrupts unmasked _____ ; set up the timer ; timer period set by values in PRD and TDDR ; period = (CLKOUT1 period) x (1+PRD) x (1+TDDR) examples for TMS320C203 with 40MHz main clock ; Timer rate TDDR PRD ; 80 kHz 9 24 (18h) ; 50 kHz 9 39 (27h) ;-----prd_val.equ 0018h tcr_val.equ 0029h tcr_val.equ 0029h splk #0000h, temp; clear timer splk #prd_val, temp; set PRD out temp, PRD splk #tcr_val, temp; set TDDR, and TRB=1 for auto-reload out temp, TCR ; ---; Configure IO0/1 as outputs to be : ; IOO CS - and set high ; IO1 LDAC - and set high ;----_____ _____ temp, ASPCR; configure as output in lacl temp #0003h or sacl temp out temp, ASPCR temp, IOSR; set them high in lacl temp #0003h or sacl temp out temp, IOSR _____ ;-----_____ ; set up serial port for ; SSPCR.TXM=1 Transmit mode - generate FSX ; SSPCR.MCM=1 Clock mode - internal clock source ; SSPCR.FSM=1 Burst mode ;-splk #0000Eh, temp temp, SSPCR; reset transmitter out splk #0002Eh, temp out temp,SSPCR ;-; reset the rolling pointer _____ lacl #000h sacl r_ptr ; ---; enable interrupts _____ _____ ; clrc INTM ; enable maskable interrupts ;_____ _____ ; loop forever!



TLV5614 2.7-V TO 5.5-V 12-BIT 3-µS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN SLAS188B – SEPTEMBER 1998 – REVISED APRIL 2003

APPLICATION INFORMATION

_	; next	wait for interrupt
; all else f	fails stop her	
, done b	done ;1	hang there
,	Service Routi	
;		
intl ret int23 ret timer isr:	; do not ; do not	hing and return hing and return
<pre>lacl id and #0 sacl te out te out te out te and #0 sacl te out te lacl r add #2 sacl D2 add #0 sacl D2 sacl D2</pre>	osr_stat ; OFFFDh ; emp ; emp, IOSR ; 0002h ; emp ; emp, IOSR ; OFFFEh ; emp, IOSR ; _ptr ; sinevals ; ACa_ptr ; 08h ; ACc_ptr 08h ; ACb_ptr ; ar0 ; r0, DACa_ptr ;	set IO1 - LDAC high reset IO0 - CS low
	emp ; emp, SDTR ;	send data
TLV5614/04 : we need a CI compatibilit	interface does LKX -ve edge t ty. 016h ;	mission to complete before writing next word to the SDTR.; s not allow the use of burst mode with the full packet; rate, as to clock in last bit before FS goes high again,; to allow SPI wait long enough for this configuration of MCLK/CLKOUT1 rate
lacl * or #I sacl te out te	; DACb_control; emp ; emp, SDTR ; 016h ;	ar0 points to DAC a sample get DAC a sample into accumulator OR in DAC B control bits send data wait long enough for this configuration of MCLK/CLKOUT1 rate
lacl *	; DACc_control; temp; temp, SDTR; #016h;	ar0 points to dac a sample get DAC a sample into accumulator OR in DAC C control bits send data wait long enough for this configuration of MCLK/CLKOUT1 rate

TLV5614 2.7-V TO 5.5-V 12-BIT 3- μ S QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

SLAS188B - SEPTEMBER 1998 - REVISED APRIL 2003

APPLICATION INFORMATION

; DAC D lar lacl or sacl	<pre>* ; #dacd_control;</pre>	otr; ar0 points to DAC a sample get DAC a sample into accumulator OR in DAC D control bits
out	temp, SDTR ;	send data
and sacl	#1h ; #001Fh ; r_ptr ; #016h ;	load rolling pointer to accumulator increment rolling pointer count 0-31 then wrap back round store rolling pointer wait long enough for this configuration of MCLK/CLKOUT1 rate
	e CS high again	
or sacl out	#0001h ; temp ; temp, IOSR ;	
clrc ret .end		re-enable interrupts return from interrupt



TLV5614 interfaced to MCS®51 microcontroller

hardware interfacing

Figure 18 shows an example of how to connect the TLV5614 to an MCS[®]51 Microcontroller. The serial DAC input data and external control signals are sent via I/O Port 3 of the controller. The serial data is sent on the RxD line, with the serial clock output on the TxD line. Port 3 bits 3, 4, and 5 are configured as outputs to provide the DAC latch update (LDAC), chip select (\overline{CS}) and frame sync (FS) signals for the TLV5614. The active low power down pin (\overline{PD}) of the TLV5614 is pulled high to ensure that the DACs are enabled.

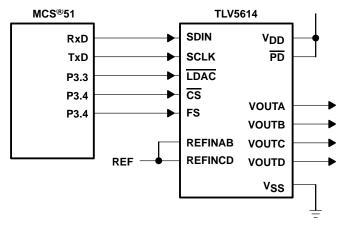


Figure 19. TLV5614 Interfaced With MCS[®]51

software

The example is the same as for the TMS320C203 in this data sheet, but adapted for a MCS[®]51 controller. It generates a differential in-phase (sine) signal between the VOUTA and VOUTB pins, and its quadrature (cosine) signal is the differential signal between VOUTC and VOUTD.

The on-chip timer is used to generate interrupts at a fixed frequency. The related interrupt service routine pulses $\overline{\text{LDAC}}$ low to update all 4 DACs simultaneously, then fetches and writes the next sample to all 4 DACs. The samples are stored as a look-up table, which describes one full period of a sine wave.

The serial port of the controller is used in Mode 0, which transmits 8 bits of data on RxD, accompanied by a synchronous clock on TxD. Two writes concatenated together are required to write a complete word to the TLV5614. The \overline{CS} and FS signals are provided in the required fashion through control of IO port 3, which has bit addressable outputs.



TLV5614 2.7-V TO 5.5-V 12-BIT 3- μ S QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

SLAS188B - SEPTEMBER 1998 - REVISED APRIL 2003

APPLICATION INFORMATION

_____ ;-----; Processor: 80C51 ; Description: ; This program generates a differential in-phase (sine) on (OUTA-OUTB) ; and it's quadrature (cosine) as a differential signal on (OUTC-OUTD). ; © 1998, Texas Instruments Inc. ;_____ ------_____ NAME GENIQ MAIN SEGMENT CODE ISR SEGMENT CODE SINTBL SEGMENT CODE VAR1 SEGMENT STACK SEGMENT DATA IDATA ;-----_____ ; Code start at address 0, jump to start ; ----_____ CSEG AT 0 LJMP start ; Execution starts at address 0 on power-up. ;______ ; Code in the timer0 interrupt vector ;------_____ CSEG AT OBH ; Jump vector for timer 0 interrupt is 000Bh LJMP timer0isr ; _ _ _ _ _____ _____ ; Global variables need space allocated VAR1 RSEG temp_ptr: DS 1 rolling_ptr: DS 1 -------Interrupt service routine for timer 0 interrupts ;-----_____ RSEG ISR timer0isr: PUSH PSW PUSH ACC ; pulse LDAC low CLR TNT1 SETB ; to latch all 4 previous values at the same time INT1 ; 1st thing done in timer isr => fixed period CLR ΤO ; set CS low ; The signal to be output on each DAC is a sine function. ; One cycle of a sine wave is held in a table @ sinevals ; as 32 samples of msb, lsb pairs (64 bytes). ; We have ; one pointer which rolls round this table, rolling_ptr, ; incrementing by 2 bytes (1 sample) on each interrupt (at the end of ; this routine). The DAC samples are read at an offset to this rolling pointer: ; ; DAC Function Offset from rolling_ptr А sine 0 ; ; B inverse sine 32 С ; cosine 16 inverse cosine48 ; D MOV DPTR, #sinevals; set DPTR to the start of the table ; of sine signal values R7,rolling_ptr; R7 holds the pointer MOV ; into the sine table MOV A,R7 ; get DAC A msb ; msb of DAC A is in the ACC MOVC A,@A+DPTR



	CLR	Т1	; transmit it - set FS low
	MOV	SBUF,A	; send it out the serial port
	INC MOV MOVC A_MSB_	A,@A+DPTR	; increment the pointer in R7 ; to get the next byte from the table ; which is the lsb of this sample, now in ACC
	JNB CLR MOV	TI,A_MSB_TX TI	; wait for transmit to complete ; clear for new transmit ; and send out the lsb of DAC A
	; DAC	the sine table A,R7 A,#0FH A,#03FH	be taken from 16 bytes (8 samples) further on - this gives a cosine function ; pointer in R7 ; add 15 - already done one INC ; wrap back round to 0 if > 64 ; pointer back in R7
	MOVC ORL	A,#01H	; get DAC C msb from the table ; set control bits to DAC C address
A_I	LSB_TX: JNB SETB CLR T1	TI,A_LSB_TX T1	; wait for DAC A lsb transmit to complete ; toggle FS
C	CLR MOV INC MOV	TI SBUF,A R7 A,R7 A,@A+DPTR	; clear for new transmit ; and send out the msb of DAC C ; increment the pointer in R7 ; to get the next byte from the table ; which is the lsb of this sample, now in ACC
C_1	JNB CLR MOV	TI,C_MSB_TX TI	; wait for transmit to complete ; clear for new transmit ; and send out the lsb of DAC C
	; DAC ; in t MOV ADD ANL	the sine table A,R7 A,#0FH A,#03FH	be taken from 16 bytes (8 samples) further on - this gives an inverted sine function ; pointer in R7 ; add 15 - already done one INC ; wrap back round to 0 if > 64 ; pointer back in R7
	MOVC ORL		; get DAC B msb from the table ; set control bits to DAC B address
C_I	LSB_TX: JNB SETB CLR CLR MOV	TI,C_LSB_TX T1 T1 TI	<pre>; wait for DAC C lsb transmit to complete ; toggle FS ; clear for new transmit ; and send out the msb of DAC B</pre>
	; get INC MOV MOVC	DAC B LSB R7 A,R7 A,@A+DPTR	; increment the pointer in R7 ; to get the next byte from the table ; which is the lsb of this sample, now in ACC
B_1	ASB_TX: JNB CLR MOV		; wait for transmit to complete ; clear for new transmit ; and send out the lsb of DAC B
	; DAC	D next D codes should the sine table	be taken from 16 bytes (8 samples) further on - this gives an inverted cosine function



SLAS188B - SEPTEMBER 1998 - REVISED APRIL 2003

APPLICATION INFORMATION

MOV A,R7 ; pointer in R7 A,#0FH ADD ; add 15 - already done one INC A, #03FH; wrap back round to 0 if > 64 ANL R7,A ; pointer back in R7 A,@A+DPTR ; get DAC D msb from the table R7,A MOV MOVC ; set control bits to DAC D address A,#03H ORL B LSB TX: JNB TI,B_LSB_TX ; wait for DAC B lsb transmit to complete SETB т1 ; toggle FS т1 CLR CLR TI ; clear for new transmit MOV SBUF, A ; and send out the msb of DAC D TNC R7 ; increment the pointer in R7 R7, increment the pointer in R7A,R7; to get the next byte from the tableA,@A+DPTR; which is the lsb of this sample, now in ACC MOV MOVC D_MSB_TX: JNB TI,D_MSB_TX ; wait for transmit to complete ; clear for new transmit CLR ΤT MOV SBUF,A ; and send out the lsb of DAC D ; increment the rolling pointer to point to the next sample ; ready for the next interrupt A,rolling_ptr MOV ; add 2 to the rolling pointer ; wrap back round to 0 if > 64 A,#02H ADD ANL A,#03FH rolling_ptr,A; store in memory again MOV D_LSB_TX: JNB TI,D_LSB_TX ; wait for DAC D lsb transmit to complete ; clear for next transmit CLR ΤI ; FS high SETB т1 т0 ; CS high SETB POP ACC POP PSW RETI ;------; Stack needs definition RSEG STACK DS 10h ; 16 Byte Stack! ;------; Main program code ; -RSEG MAIN start: MOV SP,#STACK-1 ; first set Stack Pointer CLR A SCON,A ; set serial port 0 to mode 0 TMOD,#02H ; set timer 0 to mode 2 - auto-reload TH0,#038H ; set TH0 for 5kHs interrupts MOV MOV MOV ; set LDAC = 1 ; set FS = 1 INT1 SETB SETB т1 ; set CS = 1 SETB т0 ; enable timer 0 interrupts ; enable all interrupts SETB ETO SETB ΕA MOV rolling_ptr,A; set rolling pointer to 0 SETB TR0 ; start timer 0 always: SJMP always ; while(1) ! RET ;_____ _____ ; Table of 32 sine wave samples used as DAC data ;-RSEG SINTBL



sineval	ls:
DW	01000H
DW	0903EH
DW	05097H
DW	0305CH
DW	0B086H
DW	070CAH
DW	OFOEOH
DW	0F06EH
DW	0F039H
DW	0F06EH
DW	OFOEOH
DW	070CAH
DW	0B086H
DW	0305CH
DW	05097H
DW	0903EH
DW	01000H
DW	06021H
DW	0A0E8H
DW	0C063H
DW	040F9H
DW	080B5H
DW	0009FH
DW	00051H
DW	00026H
DW	00051H
DW	0009FH
DW	080B5H
DW	040F9H
DW	0C063H
DW	0A0E8H
DW	06021H
END	

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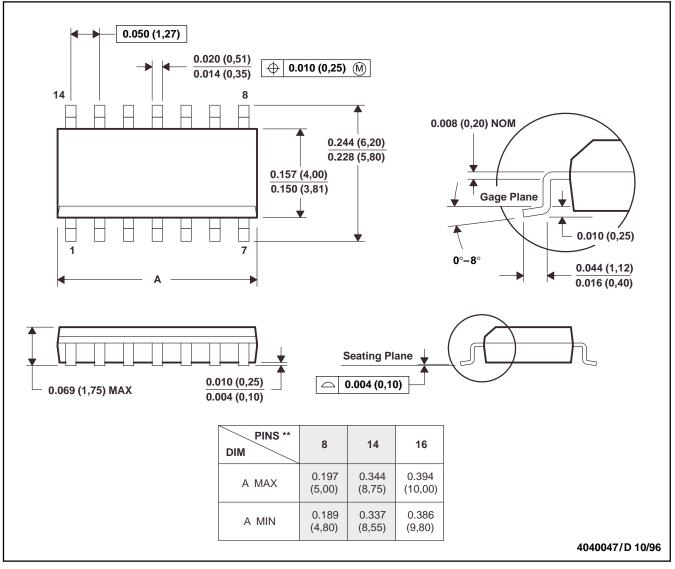
SLAS188B - SEPTEMBER 1998 - REVISED APRIL 2003

MECHANICAL DATA

D (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

14 PIN SHOWN



NOTES: D. All linear dimensions are in inches (millimeters).

E. This drawing is subject to change without notice.

F. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).

G. Falls within JEDEC MS-012



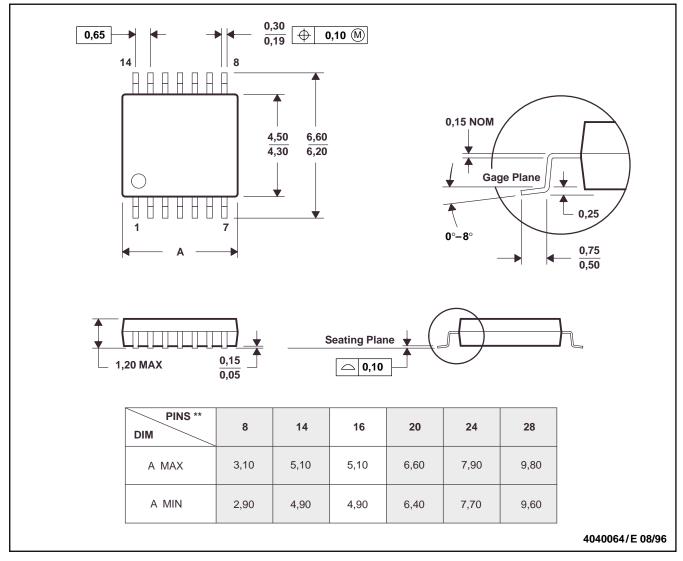
TLV5614 2.7-V TO 5.5-V 12-BIT 3-µS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS

WITH POWER DOWN SLAS188B – SEPTEMBER 1998 – REVISED APRIL 2003

MECHANICAL DATA

PLASTIC SMALL-OUTLINE PACKAGE

PW (R-PDSO-G**) 14 PIN SHOWN



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153



TEXAS INSTRUMENTS

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
TLV5614CD	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5614CDG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5614CPW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5614CPWG4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5614CPWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5614CPWRG4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5614ID	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5614IDG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5614IDR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5614IDRG4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5614IPW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5614IPWG4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5614IPWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5614IPWRG4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM

⁽¹⁾ The marketing status values are defined as follows:

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⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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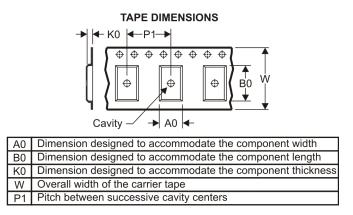
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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV5614CPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TLV5614IDR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
TLV5614IPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

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PACKAGE MATERIALS INFORMATION

25-Sep-2009



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TLV5614CPWR	TSSOP	PW	16	2000	346.0	346.0	29.0
TLV5614IDR	SOIC	D	16	2500	346.0	346.0	33.0
TLV5614IPWR	TSSOP	PW	16	2000	346.0	346.0	29.0

MECHANICAL DATA

MTSS001C - JANUARY 1995 - REVISED FEBRUARY 1999

PW (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

14 PINS SHOWN



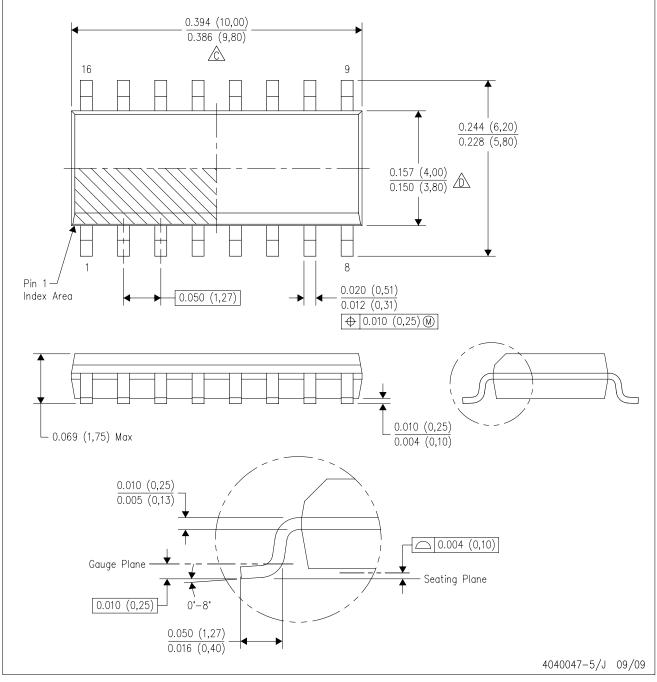
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- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.
- D. Falls within JEDEC MO-153



D (R-PDSO-G16)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

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- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 (0,15) per end.
- Body width does not include interlead flash. Interlead flash shall not exceed .017 (0,43) per side.
- E. Reference JEDEC MS-012 variation AC.



D(R-PDSO-G16)



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Refer to IPC7351 for alternate board design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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